COURSE OUTLINE

- Introduction
- Signals and Noise
- Filtering: 1/f Noise and High-Pass Filters 1 - HPF1
- Sensors and associated electronics

1/f Noise and High-Pass Filters 1

- 1/f Noise features
- 1/f Noise band-limits and power
- 1/f Noise Filtering

- Intrinsic High-Pass Filtering by Correlated Double Sampling (CDS)
- Correlated Double Sampling with Filtered Baseline (CDS-FB)
- Correlated Double Filtering (CDF)

1/f Noise features

1/f Noise

Random fluctuations with power spectral density

$$S(f) \propto \frac{1}{|f|}$$

- first reported in 1925 as «flicker noise» in electronic vacuum tubes
- ubiquitous, observed in all electronic devices
- with very **different intensity in different devices**:
  very strong in MOSFETs; moderate in Bipolar Transistors BJTs;
  moderate in carbon resistors; ultra-weak in metal-film resistors; etc.
- observed in many cases also **outside electronics:**
  cell membrane potential; insulin level in diabetic blood; brownian motion;
  solar activity; intensity of white dwarf stars; ocean current flux;
  frequency of atomic clocks; ... and many others

- Basic **distinction** between 1/f and white noise:
  time span of interdependence between samples
  for **white** noise: samples are **uncorrelated even at short** time distance
  for **1/f** noise: samples are strongly **correlated even at long** time distance

1/f Noise features

- The real observed power density at low frequency is often not exactly $\propto \frac{1}{f}$

  but rather $\propto \frac{1}{|f|^{\alpha}}$ with α close to unity, i.e. 0,8 < α <1,2

  anyway the behavior of such noise is **well approximated by *1/f*** density

- 1/f noise arises from physical processes that generate a **random superposition** of elementary pulses with **random pulse duration** ranging from **very short to very long**.

E.g. in MOSFETs 1/f noise arises because:

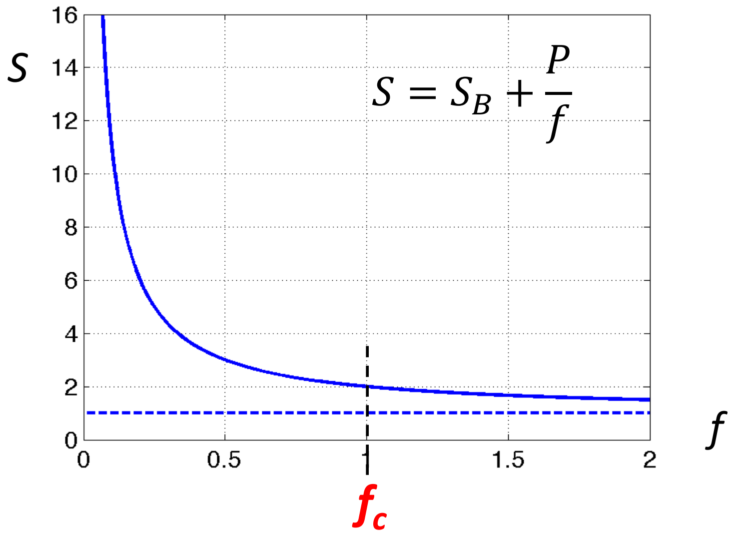
a) carriers traveling in the conduction channel are randomly captured by local trap levels in the oxide
b) trapped carriers are later released with a random delay
c) the level mean delay strongly depends on how far-off is from the silicon surface is the level in the oxide
d) trap levels are distributed from very near to very far from silicon, delays are correspondingly distributed from very short to very long

1/f Noise specification

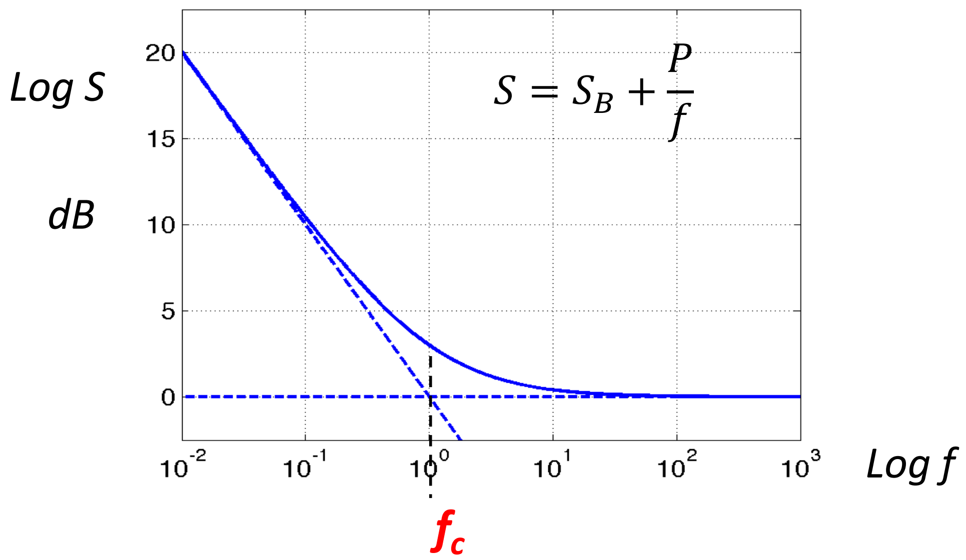
- Spectral density $S_f(f) = \frac{P}{f}$ noise power $\overline{n_f^2} = \int_0^{+\infty} \frac{P}{f}\, df$ (with unilateral S_f)

- circuits and devices have both 1/f noise S_f and white noise S_B

Linear diagram



Bode diagram



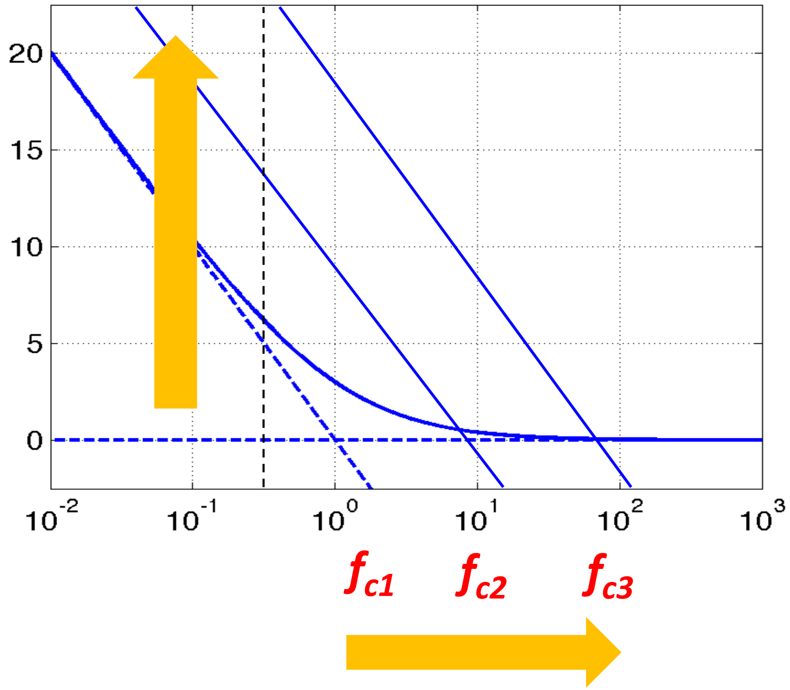
- S_f is specified in relative terms referred to the white noise S_B by specifing the «corner frequency» f_c at which $\boldsymbol{S_f = S_B}$

1/f Noise specification

- The **1/f noise corner frequency** f_c is so defined by

$$\frac{P}{|f_c|} = S_B \qquad \text{hence} \qquad P = S_B f_c$$

NB: the **higher** is frequency f_c the **stronger** is the role of 1/f noise and for a given S_B, the higher is the intensity P



Typical values for low-noise voltage amplifiers

- S_B a few 10^{-18} V^2/Hz

  $\sqrt{S_B}$ a few $\frac{nV}{\sqrt{Hz}}$

- f_c 10Hz to 10kHz

1/f Noise band-limits and power

1/f Noise bandlimits and power

The ideal 1/f noise spectrum runs from f = 0 to f → ∞ and has divergent power $\overline{n_f^2} \rightarrow \infty$ (recall that also the ideal white spectrum has $\overline{n_B^2} \rightarrow \infty$)

$$\overline{n_f^2} = \int_0^{\infty} \frac{P}{f}\, df \rightarrow \infty$$

A **real** 1/f noise spectrum has **span limited** at both ends and is **not divergent**.

If there is **wide spacing** between the high-frequency and low-frequency limitations they can be **approximated by sharp cutoff** at low frequency f_i and high frequency $f_s >> f_i$ and the noise power can be evaluated as *

$$\overline{n_f^2} \approx \int_{f_i}^{f_s} \frac{P}{f}\, df = P \ \ln\left(\frac{f_s}{f_i}\right) = S_B f_c \ \ln\left(\frac{f_s}{f_i}\right)$$

The actual 1/f bandlimits f_s and/or f_i of given filter types will be illustrated later.

- Beware !

  ONLY if $f_S >> f_i$ the sharp cutoff gives a **GOOD APPROXIMATION** of the noise power (we are considering a **rectangle** as shape of the cutoff in the integral calculation)

1/f Noise bandlimits and power

In cases with **widely spaced bandlimits** $f_S >> f_i$ the 1/f noise power $\overline{n_f^2}$ is

$$\overline{n_f^2} \approx \int_{f_i}^{f_S} \frac{P}{f}\, df = S_B f_c \ \ln\left(\frac{f_S}{f_i}\right)$$

NOTE THAT:

- $\overline{n_f^2}$ is divergent for $f_s \rightarrow \infty$ (like white noise).
  A limit at high frequency is necessary for avoiding divergence,
  but in real cases a finite limit always exists.

- $\overline{n_f^2}$ is divergent for $f_i \rightarrow 0$ (like random-walk noise $1/f^2$).
  A limit at low frequency is necessary for avoiding divergence,
  but we will see that in real cases there is always a finite limit

- $\overline{n_f^2}$ depends on the **ratio** f_s / f_i and **NOT the absolute values fs and** f_i

DATASHEET

ISL28134

5V Ultra Low Noise, Zero Drift Rail-to-Rail Precision Op Amp

FN6957
Rev 6.00
October 14, 2014

The ISL28134 is a single, chopper-stabilized zero drift operational amplifier optimized for single and dual supply operation from 2.25V to 6.0V and ±1.125V and ±3.0V. The ISL28134 uses auto-correction circuitry to provide very low input offset voltage, drift and a reduction of the 1/f noise corner below 0.1Hz. The ISL28134 achieves ultra low offset voltage, offset temperature drift, wide gain bandwidth and rail-to-rail input/output swing while minimizing power consumption.

The ISL28134 is ideal for amplifying the sensor signals of analog front-ends that include pressure, temperature, medical, strain gauge and inertial sensors down to the µV levels.

The ISL28134 can be used over standard amplifiers with high stability across the industrial temperature range of -40°C to +85°C and the full industrial temperature range of -40°C to +125°C. The ISL28134 is available in an industry standard pinout SOIC and SOT-23 packages.

Applications

- Medical instrumentation
- Sensor gain amps
- Precision low drift, low frequency ADC drivers
- Precision voltage reference buffers
- Thermopile, thermocouple, and other temperature sensors front-end amplifiers
- Inertial sensors
- Process control systems
- Weight scales and strain gauge sensors

Features

- Rail-to-rail inputs and outputs
  - CMRR at V_{CM} = 0.1V beyond V_S . . . . 135dB, typ
  - V_{OH} and V_{OL} . . . . 10mV from V_S, typ
- No 1/f noise corner down to 0.1Hz
  - Input noise voltage . . . . 10nV/√Hz at 1kHz
  - 0.1Hz to 10Hz noise voltage . . . . 250nV_{P-P}
- Low offset voltage . . . . 2.5µV, Max
- Superb offset drift . . . . 15nV/°C, Max
- Single supply . . . . 2.25V to 6.0V
- Dual supply . . . . ±1.125V to ±3.0V
- Low I_{CC} . . . . 675µA, typ
- Wide bandwidth 3.5MHz
- Operating temperature range
  - Industrial . . . . -40°C to +85°C
  - Full industrial . . . . -40°C to +125°C
- Packaging
  - Single: SOIC, SOT-23

Related Literature

- AN1641, “ISL28134SOICEVAL1Z Evaluation Board User’s Guide”
- AN1560, “Making Accurate Voltage Noise and Current Noise Measurements on Operational Amplifiers Down to 0.1Hz”

1/f Noise bandlimits and power

$$\overline{n_f^2} \approx \int_{f_i}^{f_s} \frac{P}{f}\, df = S_B f_c \ \ln\left(\frac{f_s}{f_i}\right)$$

Note 1: $\overline{n_f^2}$ is **SLOWLY** divergent for $f_i \rightarrow 0$ or $f_s \rightarrow \infty$ **Logarithmic** dependence

Note 2: **reasonably approximate** bandlimits are **adequate** for estimating $\overline{n_f^2}$
it is **not necessary to know very precisely** f_s and f_i

EXAMPLE: 1/f noise with $\sqrt{P} = \sqrt{S_B f_C} = 100nV$

filtered with f_i = 1kHz and f_s = 10kHz (f_s / f_i = **10**)

$$\sqrt{\overline{n_{f,a}^2}} = \sqrt{2{,}3}\ \sqrt{S_B f_c} = 151nV$$

filtered with f_i = 1 Hz and f_s = 10MHz (f_s / f_i = **10^7** , i.e. **x 10^6 higher**)

$$\sqrt{\overline{n_{f,b}^2}} = \sqrt{7 \cdot 2{,}3}\ \sqrt{S_B f_c} = 401nV$$ (just **x 2,7 higher**)

1/f Noise Filtering

1/f Noise filtering and power

The **band-limits of a filter for 1/f noise** are well visualized in the **linear-log diagram** of the weighting function $|W(\ln f)|^2$

$$\overline{n_f^2} = S_B\, f_c \int_0^\infty |W(f)|^2 \frac{df}{f} = S_B\, f_c \int_{-\infty}^{\infty} |W(f)|^2 d(\ln f)$$

(beware: it's NOT A BODE diagram: the vertical scale is linear !!)

- **1/f** noise: $\overline{n_f^2}$ ∝ **area (integral) of** $|\mathbf{W}|^2$ **plot in logarithmic frequency** scale

which is different from the case of

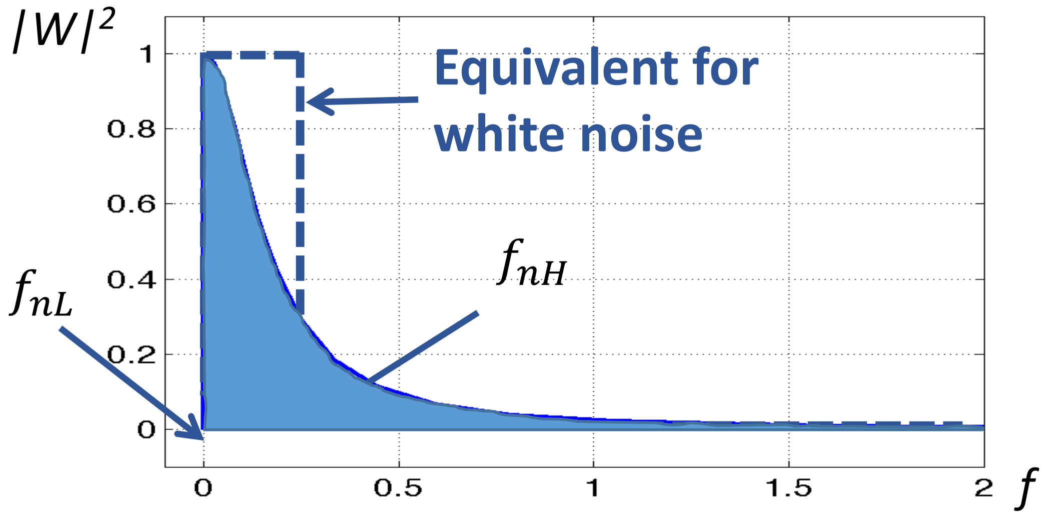
- **white** noise: $\overline{n_B^2}$ ∝ **area (integral) of** $|\mathbf{W}|^2$ **plot in linear frequency** scale

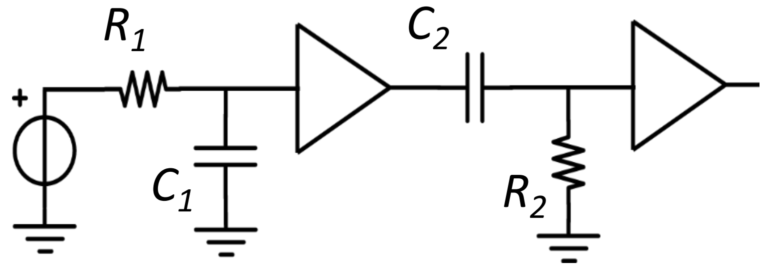
In both cases the noise power depends mainly on the **frequency span covered** by $|\mathbf{W}|^2$, delimited by upper and lower bounds in frequency. However, the frequency span is **measured differently** :

- for **white** noise, by the **difference** of the bounds
- for **1/f** noise, by the **logarithmic difference**, i.e. by the **ratio** of the bounds

Noise bandlimits: RC lowpass plus CR highpass

Lin-Lin plot



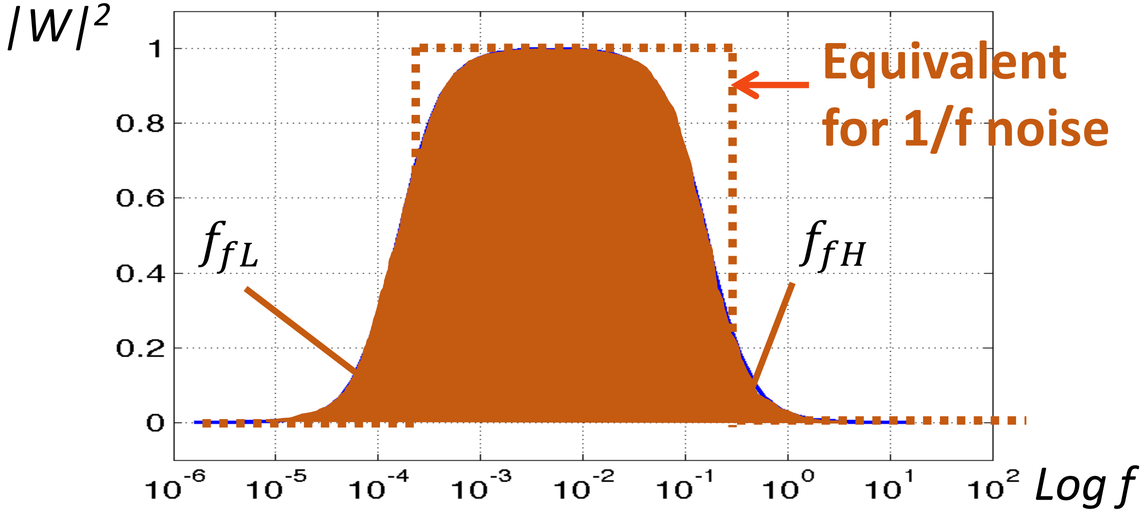


Cascaded two-cell filter:

Low-pass $T_{RC} = R_1C_1$ ($T_{R1C1} = 1$)

High-pass $T_{CR} = R_2C_2$ ($T_{C2R2} = 1000$)

Lin-Log plot



$$|W|^2 = \frac{1}{1+(2\pi f R_1 C_1)^2} \cdot \frac{(2\pi f R_2 C_2)^2}{1+(2\pi f R_2 C_2)^2}$$

$$\overline{n^2_{White}} = S_B \int_0^{\infty} |W(f)|^2 df$$

$$\overline{n_f^2} = S_B\ f_c \int_{-\infty}^{\infty} |W(f)|^2 d(\ln f)$$

Simple equivalent weighting function is **rectangular** with area and height equal to the true weighting $|W(f)|^2$

Intrinsic High-Pass Filtering
by
Correlated Double Sampling CDS

Intrinsic High-Pass Filtering

In all real cases, even with DC coupled electronics weighting is inherently **NOT extended** down to **zero frequency** because an intrinsic high-pass filtering is present in any real operation.

The intrinsic filtering action arises because:

a) operation is **started at some time before** the acquisition of the measure

b) operation is **started from zero** value

EXAMPLE: measurement of amplitude of the output signal of a DC amplifier or simply the use of a scale.

Zero-setting is mandatory: the baseline voltage is preliminary adjusted to zero, or it is measured, recorded and then subtracted from the measured signal.

It may be done a long time before the signal measurements (e.g. when the amplifier is switched on) or repeated before each measurement; it may be done manually or automated, but it must be done anyway.

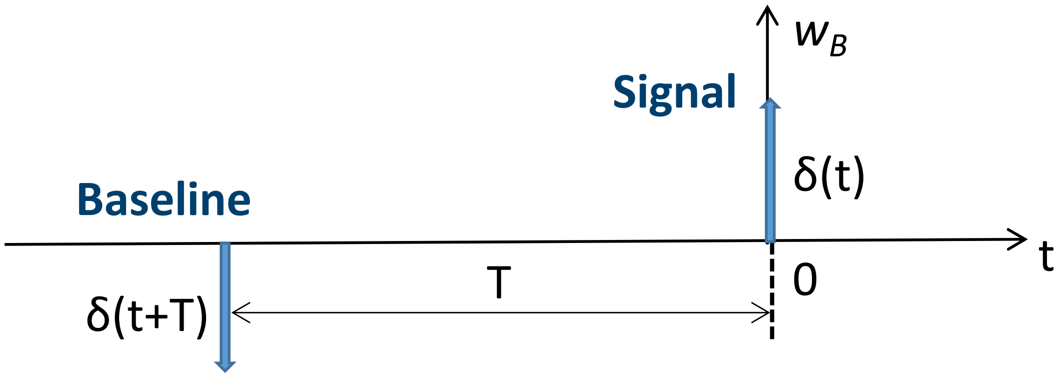
Zero-setting produces a high-pass filtering: let us analyze why and how

Zero-setting by Correlated Double Sampling (CDS)

Baseline sample is subtracted from signal sample, **both** acquired with **instant sampling**

Time-domain weighting

$$w_B(t) = \delta(t) - \delta(t+T)$$



Frequency-domain weighting

$$W_B(\omega) = F[w_B(t)] = 1 - e^{i\omega T} = 1 - \cos\omega T - i \ \sin\omega T$$

Since: $\cos\omega T = \frac{1}{2}(e^{i\omega T} + e^{-i\omega T})$ and $\sin\omega T = \frac{1}{2i}(e^{i\omega T} - e^{-i\omega T})$

For noise $|W_B(\omega)|^2 = [1 - \cos\omega T]^2 + \sin^2\omega T = 2\ [1 - \cos\omega T]$

We can also write $|W_B(\omega)|^2 = 4\sin^2\left(\frac{\omega T}{2}\right)$ [since it is *(1-cosx) = 2 sin²(x/2)*]

At ωT<< 1 a **low frequency cutoff** is produced

$$|W_B(\omega)|^2 \approx \omega^2 T^2$$

(for x << 1 it is *sinx≈x* so $4 * \frac{\omega T}{2} * \frac{\omega T}{2}$)

CDS vs. CR High-Pass Filter: Cut-Off

Baseline subtraction with delay T

$$|W_B(\omega)|^2 = 4\sin^2\left(\frac{\omega T}{2}\right)$$

at low-frequency ω << 1/T

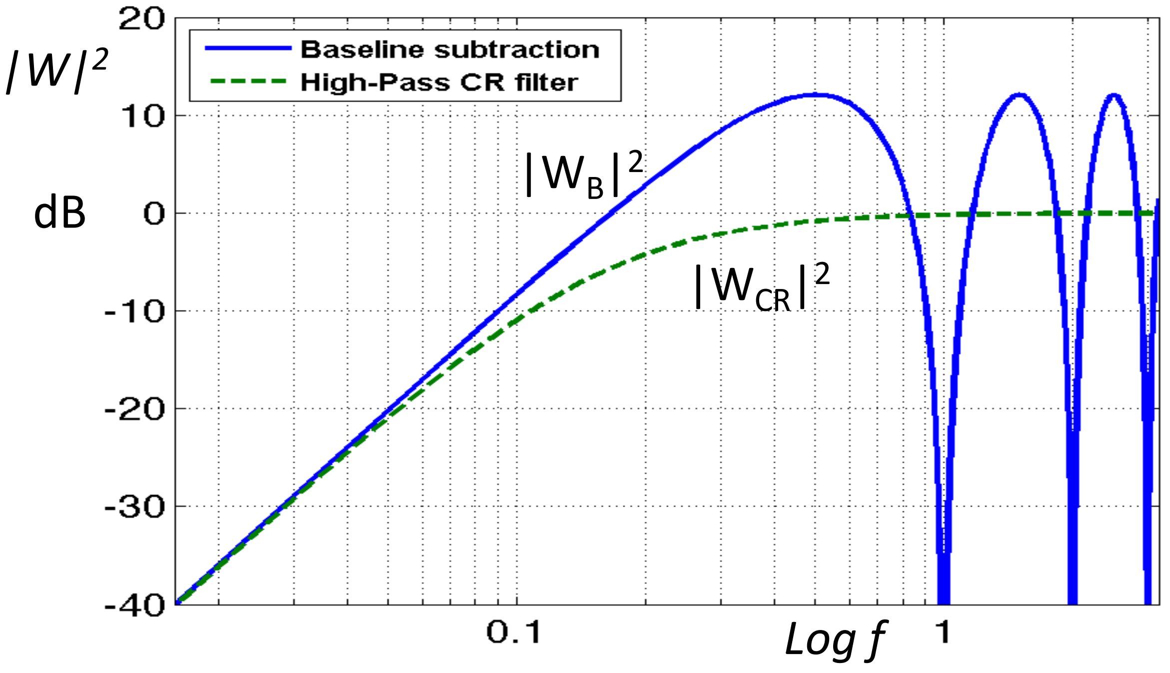
$$|W_B(\omega)|^2 \approx \omega^2 T^2$$

High-Pass CR filter (differentiator)

$$|W_{CR}(\omega)|^2 = \frac{\omega^2 R^2 C^2}{1 + \omega^2 R^2 C^2}$$

at low-frequency ω << 1/RC

$$|W_{CR}(\omega)|^2 \approx \omega^2 R^2 C^2$$

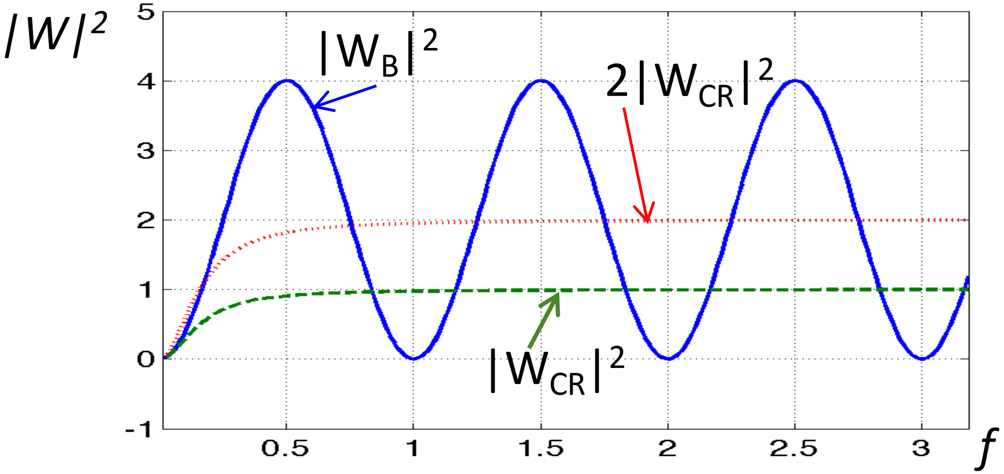


BODE DIAGRAM highlights the low-freq cutoff

Examples with equal cutoff T=RC plotted for T=1

CDS vs. CR High-Pass Filter:
White Noise

CDS vs. CR High-Pass Filter: White Noise



LIN –LIN DIAGRAM *(T=RC=1)*

white noise power ∝ area of $|W|^2$

$$\overline{n^2_{White}} = S_B \int_0^{\infty} |W(f)|^2 df$$

White noise $\overline{n^2_B}$ limited also by a low-pass f_s , but with $f_s >> 1/T$ and $f_s >> 1/RC$

$$\overline{n^2_B} = S_B \int_0^{f_S} |W(f)|^2 df \qquad \textbf{CDS: } \overline{n^2_B} = 2\, S_B f_S \qquad \textbf{CR: } \overline{n^2_B} \approx S_B f_S$$

CDS: $|W_B|^2$ oscillates around 2; its area is **exactly the same** as for a constant $|W_B|^2 = 2$

CR: $|W_{CR}|^2$ has a cutoff at low frequency $f < f_i = 1/4RC$; at higher frequency it is $|W_{CR}|^2 \approx 1$

Therefore, for white noise the output power of the CDS is **double of the unfiltered noise** and approximately double of the filtered output of the CR (actually even more than double !)

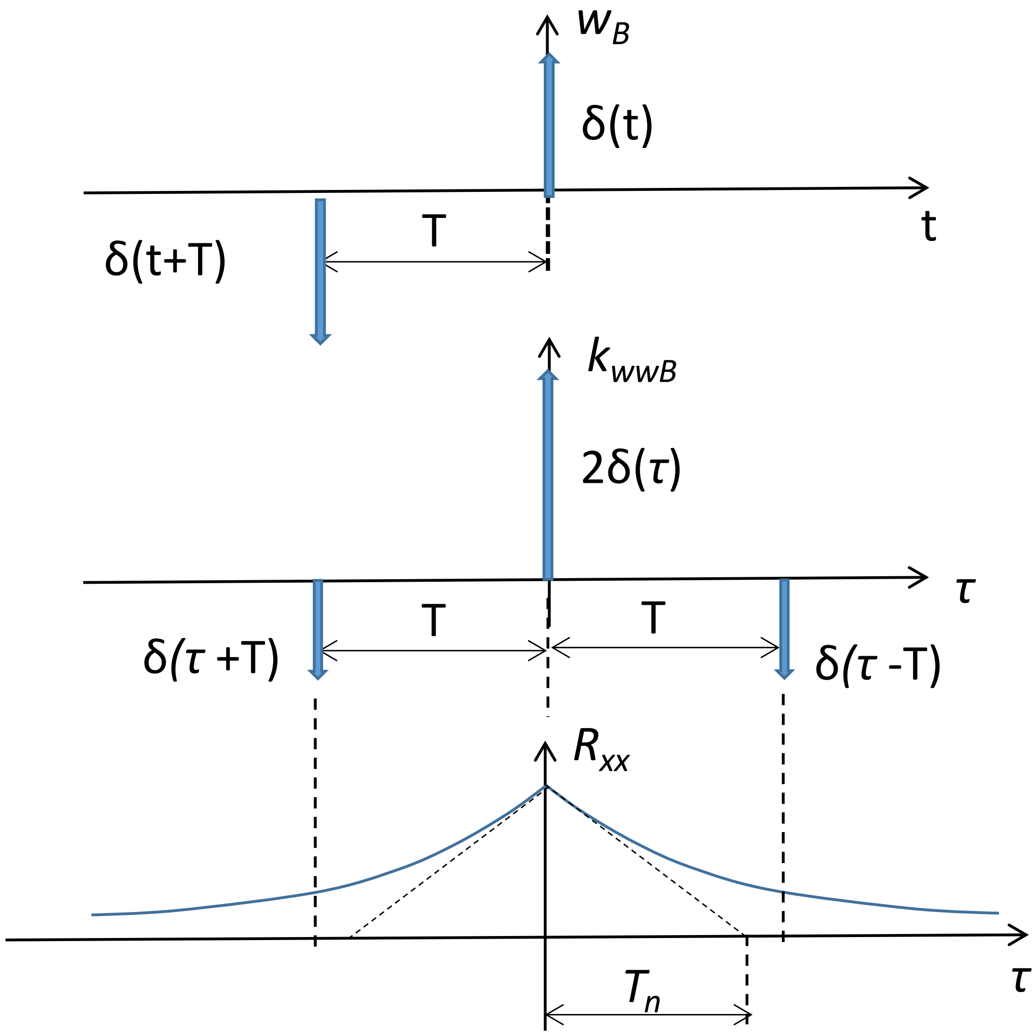
Double White noise power, as intuitive because:

1. white noise is acquired twice, in the baseline sampling and in the signal sampling.
2. The two noise samples are uncorrelated, hence their power is quadratically added.

Filtering Band-Limited White Noise by CDS

Time-domain analysis gives further insight:

$$\overline{n_B^2} = \int_{-\infty}^{\infty} R_{xx}(\tau)\ \ k_{wwB}(\tau) d\tau$$



CDS weighting function

Autocorrelation of CDS weighting function

Autocorrelation of band-limited white noise

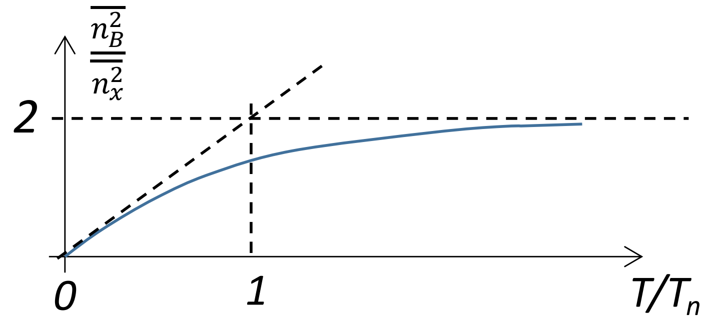
$$R_{xx}(\tau) = \overline{n_x^2} e^{-\frac{|\tau|}{T_n}}$$

T_n noise autocorrelation time

Filtering band-limited White Noise by CDS

$$\overline{n_B^2} = \int_{-\infty}^{\infty} R_{xx}(\tau) \;\; k_{wwB}(\tau) d\tau = 2\overline{n_x^2} - R_{xx}(T) - R_{xx}(-T)$$

$$\overline{n_B^2} = 2\overline{n_x^2} \cdot \left(1 - e^{-\frac{T}{T_n}}\right)$$



- Noise with **very short correlation** time (i.e. very high band-limit) is **doubled**:

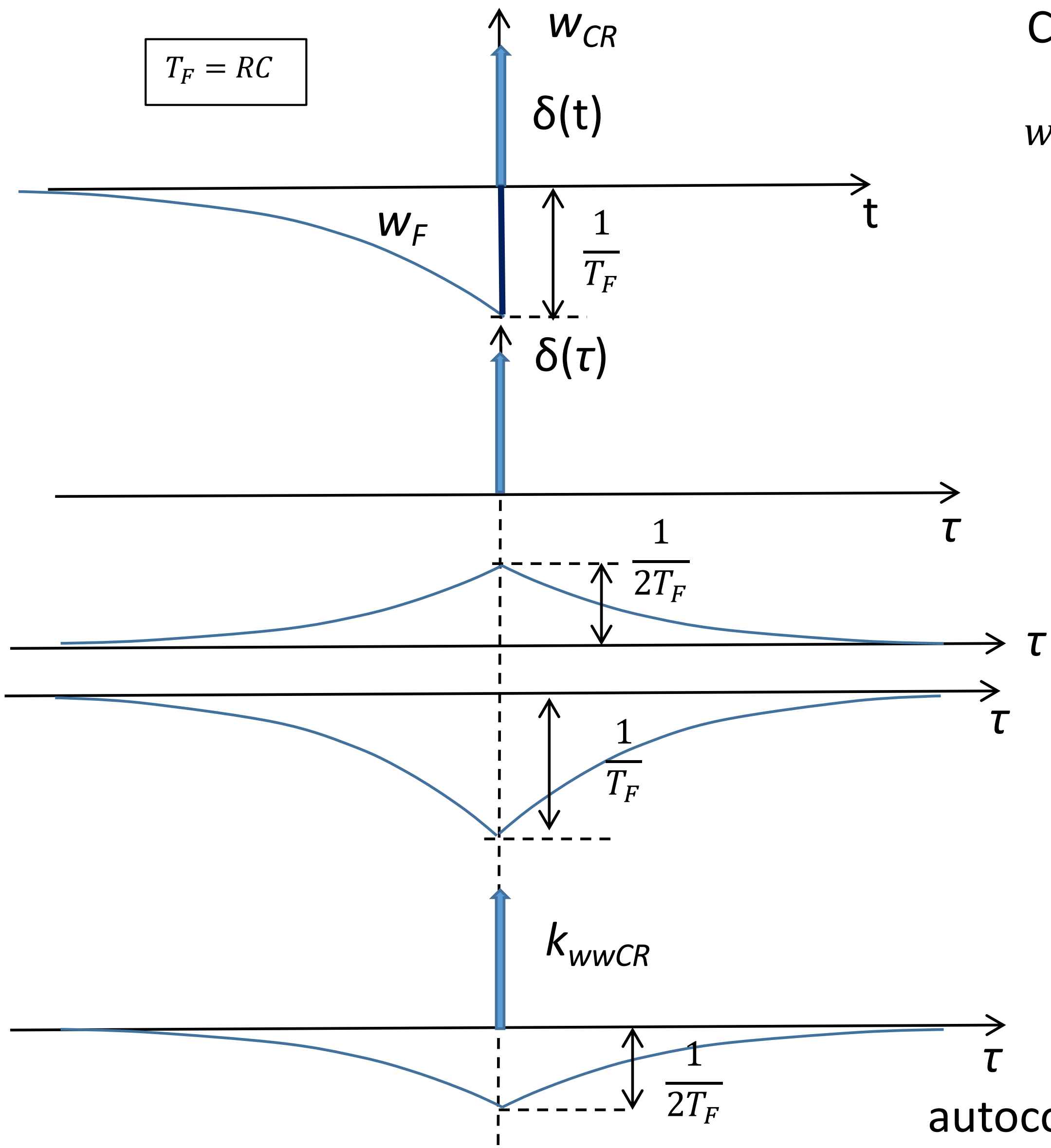
  if $T_n \ll T$ we have $\overline{n_B^2} \approx 2\overline{n_x^2}$

- Noise with **long correlation time** (i.e. very low band-limit) is **strongly attenuated**:

  if $T_n \gg T$ we have $\overline{n_B^2} \approx \overline{n_x^2} \cdot 2\frac{T}{T_n} \ll \overline{n_x^2}$

Time-domain analysis shows how with band-limited white noise the output noise power of CDS is **double of the input noise.** Let's check with a standard CR..

Filtering band-limited White Noise by CR



CR weighting function

$$w_{CR} = \delta(t) - w_F(t) = \delta(t) - \frac{1}{T_F}\exp\left(-\frac{|t|}{T_F}\right)$$

$k_{\delta\delta}=\delta(t)$

k_{FF} autocorrelation of w_F

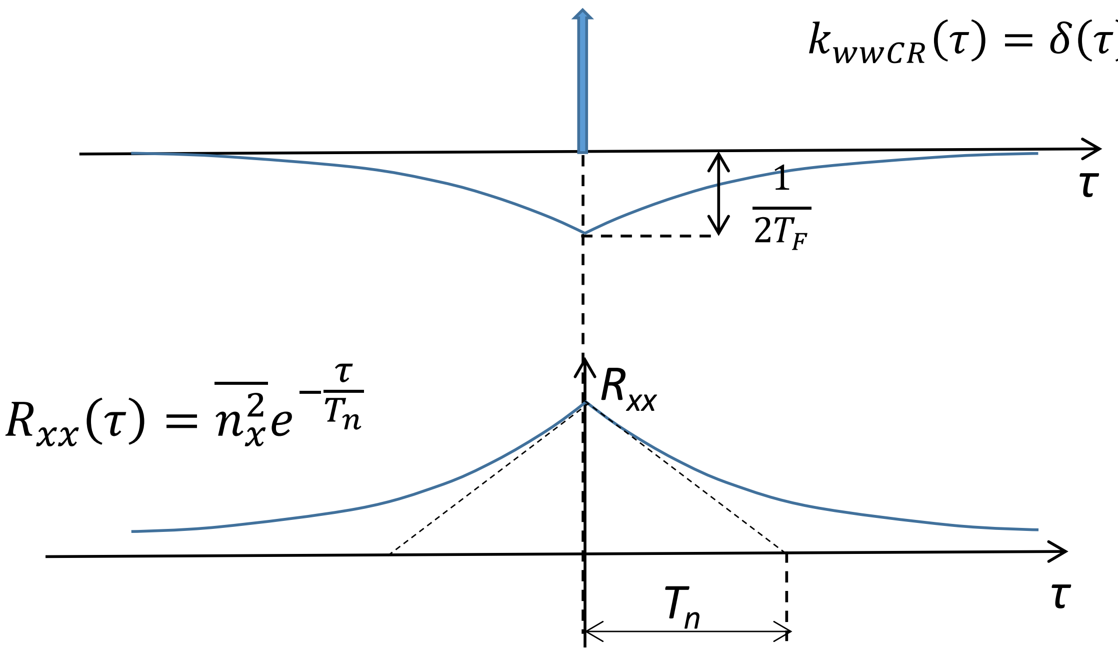
$k_{\delta F} + k_{F\delta}$ crosscorrelations δw_F and w_Fδ

autocorrelation of the CR weighting function

$$k_{wwCR} = k_{\delta\delta} + k_{FF} + k_{F\delta} + k_{\delta F}$$

Filtering band-limited White Noise by CR

$$k_{wwCR}(\tau) = \delta(\tau) - \frac{1}{2} w_F(|\tau|) = \delta(\tau) - \frac{1}{2T_F} \exp\left(-\frac{|\tau|}{T_F}\right)$$



$$\overline{n_B^2} = \int_{-\infty}^{\infty} R_{xx}(\tau) \; k_{wwCR}(\tau) d\tau =$$

$$= R_{xx}(0) - 2\int_0^{\infty} R_{xx}(\tau) \; \frac{1}{2} w_F(|\tau|) d\tau =$$

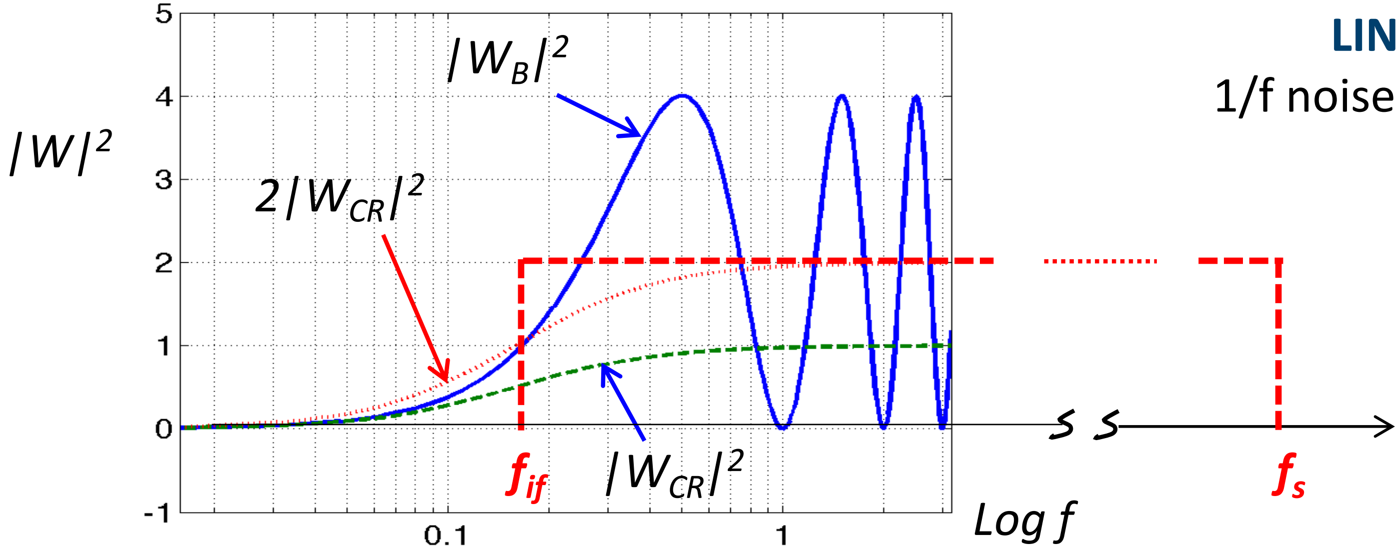
$$= \overline{n_x^2} - \overline{n_x^2} \int_0^{\infty} \frac{1}{T_F} \exp\left[-\tau\left(\frac{1}{T_n} + \frac{1}{T_F}\right)\right] d\tau$$

$$\boxed{\overline{n_B^2} = \overline{n_x^2}\left(1 - \frac{T_n}{T_F + T_n}\right) = \overline{n_x^2}\frac{T_F}{T_F + T_n}}$$

- Noise with **very short correlation time** (i.e. very high band-limit) is practically **passed as it is, not doubled** as for CDS: if $T_n \ll T_F$ we have $\overline{n_B^2} \approx \overline{n_x^2}$
- Noise with **long correlation time** (i.e. very low band-limit) is strongly **attenuated at half the level of CDS**: if $T_n \gg T_F$ we have $\overline{n_B^2} \approx \overline{n_x^2} \cdot \frac{T_F}{T_n} \ll \overline{n_x^2}$

CDS vs. CR High-Pass Filter: 1/f Noise

CDS vs. CR High-Pass Filter: 1/f noise



LIN –LOG DIAGRAM

1/f noise power ∝ area of $|W|^2$

Examples with equal cutoff T=RC plotted for T=1

1/f noise power $\overline{n_f^2}$ limited also by a low-pass f_s , but with $f_s >> 1/T$ ($f_s >> 1/RC$)

$$\overline{n_f^2} = \int_0^{f_S} |W(f)|^2 \frac{S_B f_C}{f} df = S_B f_C \int_0^{f_S} |W(f)|^2 \, d(\ln f)$$

At low frequency $f<<1/T$ the $|W_B|^2$ and $|W_{CR}|^2$ have the same cutoff (with $T=RC$).

At higher frequency W_{CR} is constant $|W_{CR}|^2 \approx 1$ whereas the $|W_B|^2$ oscillates around a mean value 2, so that :

$$\int_0^{f_S} |W_B(f)|^2 \, d(\ln f) \approx 2 \int_0^{f_S} |W_{CR}(f)|^2 \, d(\ln f)$$

Zero-setting by CDS: conclusions

- Zero-setting by **correlated double sampling (CDS)** produces a high-pass filtering action that limits the power of 1/f noise.

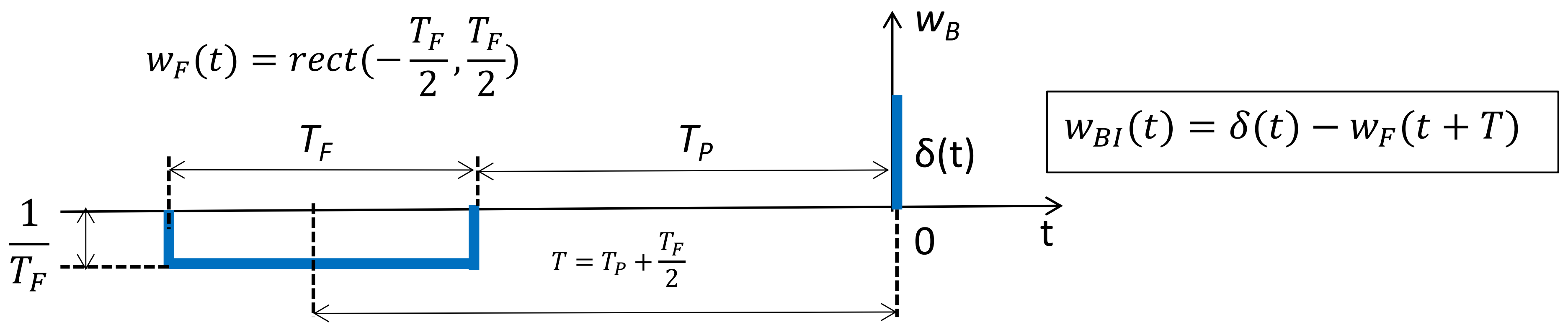
- The **interval T between zero setting and measure in most real cases is quite long** (from a few seconds to several minutes) so that the high-pass **band-limit f_{if}** is quite **low.** This is a main drawback: the filtering is **not very effective** since the 1/f noise power is limited just to a moderately low level, which may be higher than that of white noise.

- Further drawback: **with respect to CR** high-pass filter with equal bandlimit f_{if} the output noise power is **approximately double**.

Correlated Double Sampling with Filtered Baseline CDS-FB

Correlated Double Sampling with Filtered Baseline CDS-FB

- **Baseline sampling is intended to acquire the contributions of the low-frequency** components that we want subtract from the measurement.
- However, **instant sampling acquires all frequency components** at low and high frequency; by subtracting them all, we double the noise passed above the CDS cutoff.
- **Remedy: modify baseline sampling for acquiring only the low-frequency components**; that is, sample with a low-pass weighting function $w_F(t)$ with band-limit f_{Fn} , which includes only the frequencies to be subtracted.
  Example: noise with upper bandlimit f_S and baseline acquired by a Gated Integrator with narrower filtering band $f_{fn} << f_S$ (recall $f_{f\,n} = 1/2T_F$ with gate duration T_F)



NB: we still consider cases with **long interval $T_P >> T_F$** from zero-setting to measurement

CDS-FB : Cut-off and Noise Filtering

$$W_{BI}(\omega) = F[\delta(t) - w_F(t+T)] = 1 - e^{i\omega T} W_F(\omega)$$

since $W_F(\omega) = \text{sinc}\left(\frac{\omega T_F}{2}\right)$ is real and $\cos\omega T = \frac{1}{2}(e^{i\omega T} + e^{-i\omega T})$ and $\sin\omega T = \frac{1}{2i}(e^{i\omega T} - e^{-i\omega T})$

$$W_{BI}(\omega) = 1 - W_F(\omega)\cos\omega T - iW_F(\omega)\sin\omega T$$

$$|W_{BI}(\omega)|^2 = 1 + W_F^2(\omega) - 2W_F(\omega)\cos\omega T$$

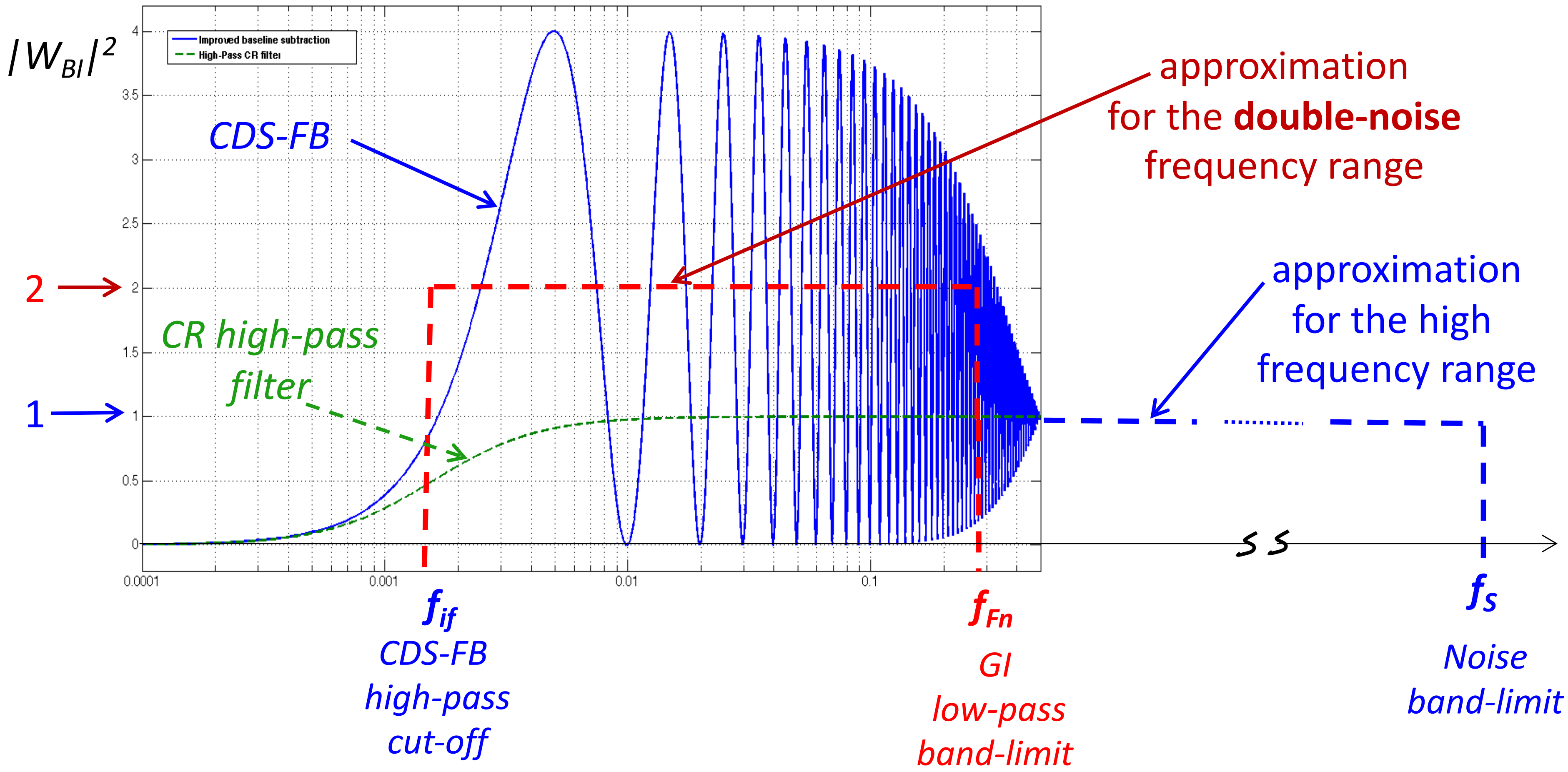
- **At low frequency** (*f << 1/T*) it is $W_F(f) \approx 1$ and W_{BI} has a high-pass cutoff equivalent to a CR differentiator with *RC=T*

$$|W_B(\omega)|^2 \approx \omega^2 T^2 = \omega^2\left(T_P + \frac{T_F}{2}\right)^2$$

$$f_{if} \approx \frac{1}{2\pi T} = \frac{1}{2\pi\left(T_P + \frac{T_F}{2}\right)}$$ cutoff frequency

- At high **frequency above the GI low-pass cutoff** ($f >> f_n = 1/2T_F$) it is $|W_F(f)| \approx 0$ so that $|W_{BI}(f)|^2 \approx 1$
- In the **intermediate range** ($1/T << f << 1/2T_F$) it is roughly $W_F(f) \approx 1$ so that roughly it is $|W_{BI}(f)|^2 \approx 2(1-\cos 2\pi f T)$. In this range the average value is about $|W_{BI}(f)|^2 \approx 2$, hence we can denote it as **double-noise range**

CDS-FB : Cut-off and Noise Filtering



Example of CDS-FB with $T_P = 101$ and $T_F = 2$

for comparison, a CR filter with equal cutoff $RC = T = T_P + T_F$ is reported

CDS-FB : output noise power

$$\overline{n^2} = \int_0^{f_S} S(f)|W_{BI}(\omega)|^2\,df = \int_0^{f_S} S(f)[1 + W_F^2 - 2W_F\ \cos 2\pi f T]\,df$$

By approximating W_{BI} as outlined, the noise power can be approximately evaluated

1/f noise

$$\overline{n^2_{f,\,BI}} \approx S_B f_C \ln\left(\frac{f_S}{f_{if}}\right) + S_B f_C \ln\left(\frac{f_{Fn}}{f_{if}}\right)$$

white noise

$$\overline{n^2_{B,BI}} \approx S_B(f_S - f_i) + S_B(f_{Fn} - f_i) \approx S_B f_S + S_B f_{Fn}$$

In **CDS-FB the noise-doubling effect is strongly reduced** with respect to the simple CDS: it occurs only in the range from the low-frequency cutoff to the GI filtering band-limit.

In cases **where the GI band-limit is much smaller than the noise band-limit** ($f_S >> f_{Fn}$) the effect of noise doubling is practically negligible

$$\overline{n^2_{f,\,BI}} \approx S_B f_C \ln\left(\frac{f_S}{f_{if}}\right) \qquad \overline{n^2_{B,BI}} \approx S_B f_S$$

Correlated Double Filtering
CDF

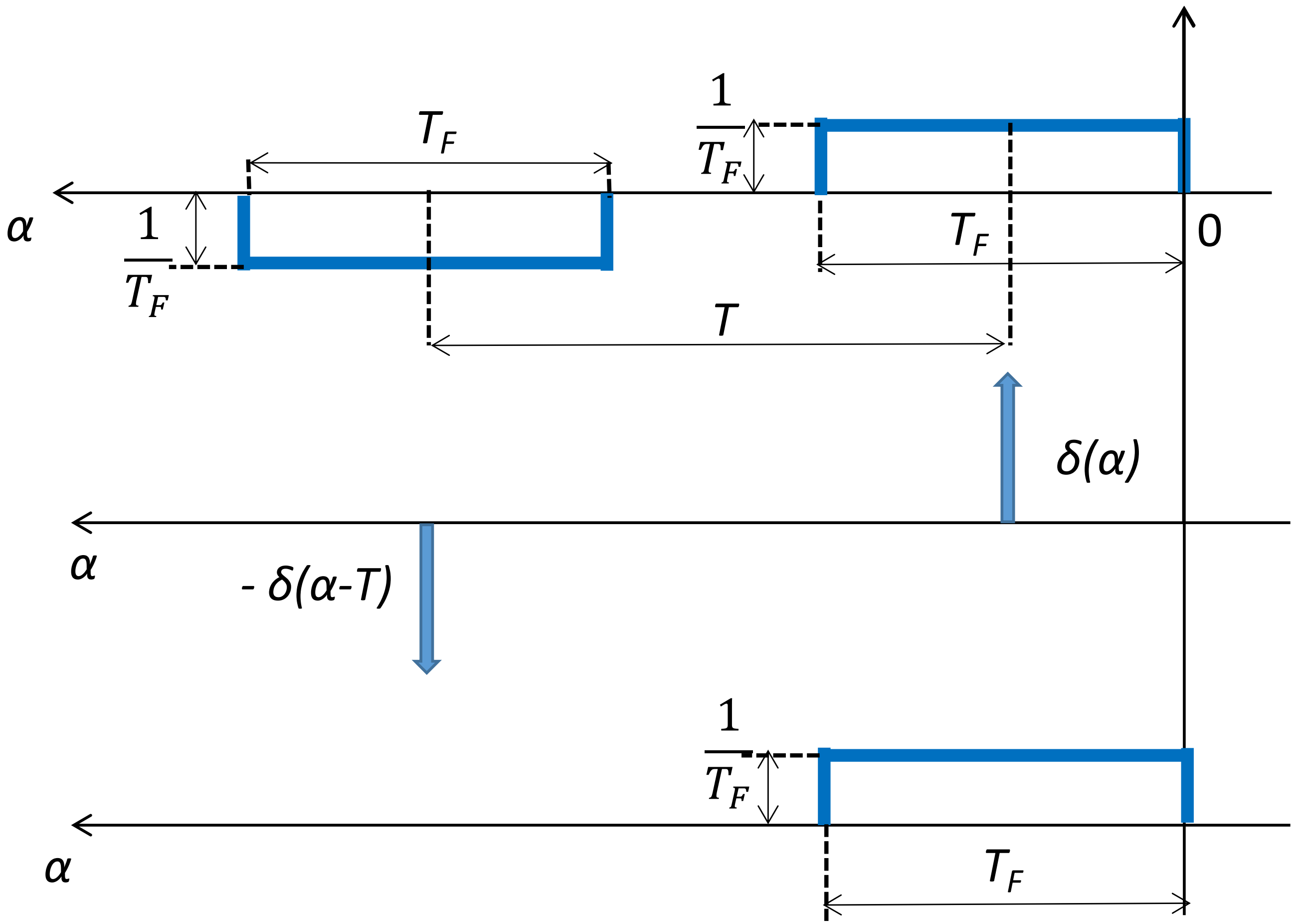
Correlated Double Filtering CDF

Normally we always use a **LPF to limit the filter the signal and limit the bandwidth of the amplifier**. The formula is still correct, also adding a LPF, if $f_S >> f_{Fn}$

What happen if f_s is comparable with f_{Fn}?

- In various cases of pulse-amplitude measurements, **filtering the signal by gated integrator (GI) is quite efficient** for the white noise component
- We can modify the CDS-FB by **subtracting from the GI acquisition of the pulse another GI acquisition over an equal interval** before the pulse to limit the 1/f
- This approach has the **same conceptual foundation as CDS, but has the two samples filtered by the GI**: it is therefore called «Correlated Double **Filtering**» CDF
- The approach can be extended to cases where a constant-parameter low-pass filter LPF is employed for filtering the white noise component and a 1/f component is also present

Correlated Double Filtering CDF



$w_{DF}(\alpha) = w_F(\alpha) - w_F(\alpha - T)$

CDF weighting (*NB: $T \geq T_F$*)

$w_{DS}(\alpha) = \delta(\alpha) - \delta(\alpha - T)$

CDS weighting

$w_F(\alpha) = rect_{0,T_F}(\alpha)$

LPF weighting

CDF weighting = convolution of CDS weighting with LPF weighting

$$w_{DF}(\alpha) = w_{DS}(\alpha) * w_F(\alpha)$$

Weighting in frequency by CDF

Since in time domain $w_{DF}(\alpha) = w_{DS}(\alpha) * w_F(\alpha)$

in frequency domain it is $W_{DF}(\omega) = W_{DS}(\omega) \cdot W_F(\omega)$

for noise computation $|W_{DF}|^2 = |W_{DS}|^2 \cdot |W_F|^2$

and since $|W_{DS}|^2 = 2(1 - \cos\omega T) = 4 sin^2(\omega T/2)$

we have

$$|W_{DF}|^2 = 2(1 - \cos \omega T) \cdot |W_F|^2 = 4 \sin^2\left(\frac{\omega T}{2}\right) \cdot |W_F|^2$$

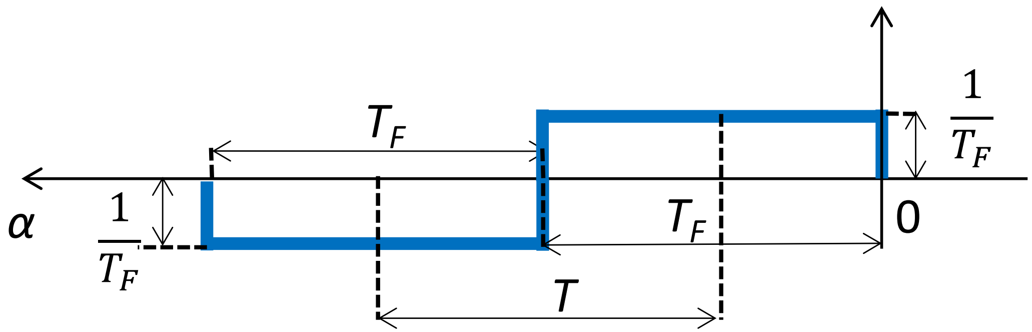
The main features of CDS reflect the fact that it is a combination of CDS and LPF :

1. The **LPF cuts the noise at high frequencies** with its LPF band-limit f_F
2. The **CDS cuts the noise at low frequencies** with its HPF band-limit $f_{iD} \approx 1/2\pi T$
3. The **CDS enhances the noise in the passband between the band-limits** (with enhancement factor roughly 2)

Weighting in frequency by CDF with GI

The previous formula is valid for **ANY** $\boldsymbol{w_F(\alpha)}$.

EXAMPLE: Let's apply the formula to the use of a Gated Integrator and **T=T$_F$**



$$w_F(\alpha) = rect_{T_F}(\alpha)$$

LPF weighting

$$w_F(\alpha) = rect_{T_F}(\alpha) \rightleftarrows W_F(\omega) = Sinc\left(\frac{\omega T_F}{2}\right)$$

$$|W_F(\omega)| = \left|Sinc\left(\frac{\omega T_F}{2}\right)\right| = \left|\frac{sin\left(\frac{\omega T_F}{2}\right)}{\frac{\omega T_F}{2}}\right|$$

Therefore

$$|W_{DF}|^2 = 2(1-\cos\omega T)\cdot|W_F|^2 = 2(1-\cos\omega T)\cdot Sinc^2\left(\frac{\omega T_F}{2}\right) = 4\sin^2\left(\frac{\omega T}{2}\right)\cdot Sinc^2\left(\frac{\omega T_F}{2}\right)$$

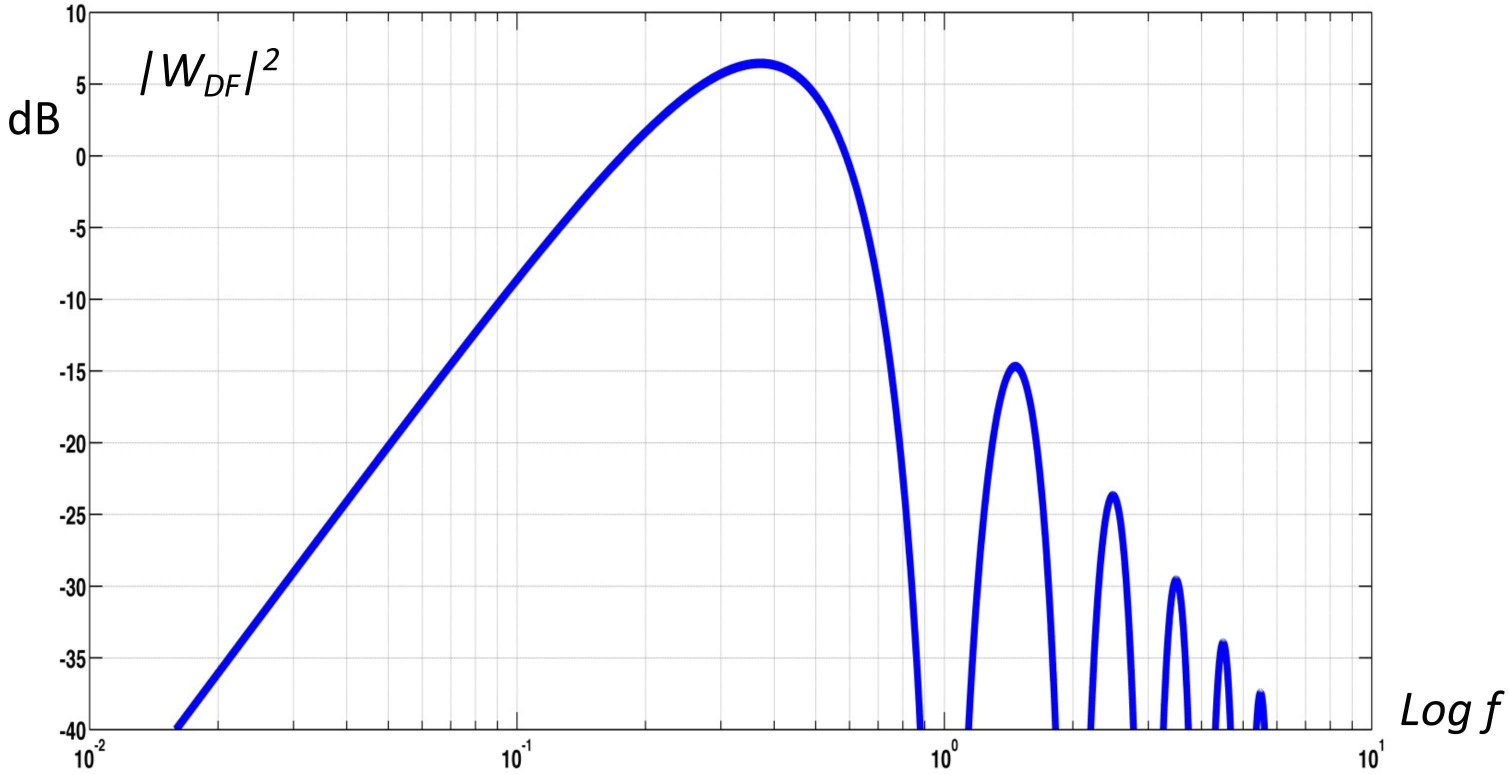
that is, with **T=T$_F$**

$$|W_{DF}|^2 = 2(1-\cos\omega T)\cdot\frac{sin^2\left(\frac{\omega T_F}{2}\right)}{\left(\frac{\omega T_F}{2}\right)^2} = 4\frac{sin^4\left(\frac{\omega T_F}{2}\right)}{\left(\frac{\omega T_F}{2}\right)^2}$$

Example of noise filtering by CDF with GI

The use of the CDF based on Gated Integrator and **$T=T_F$** is really common, but the formula is quite complicated.

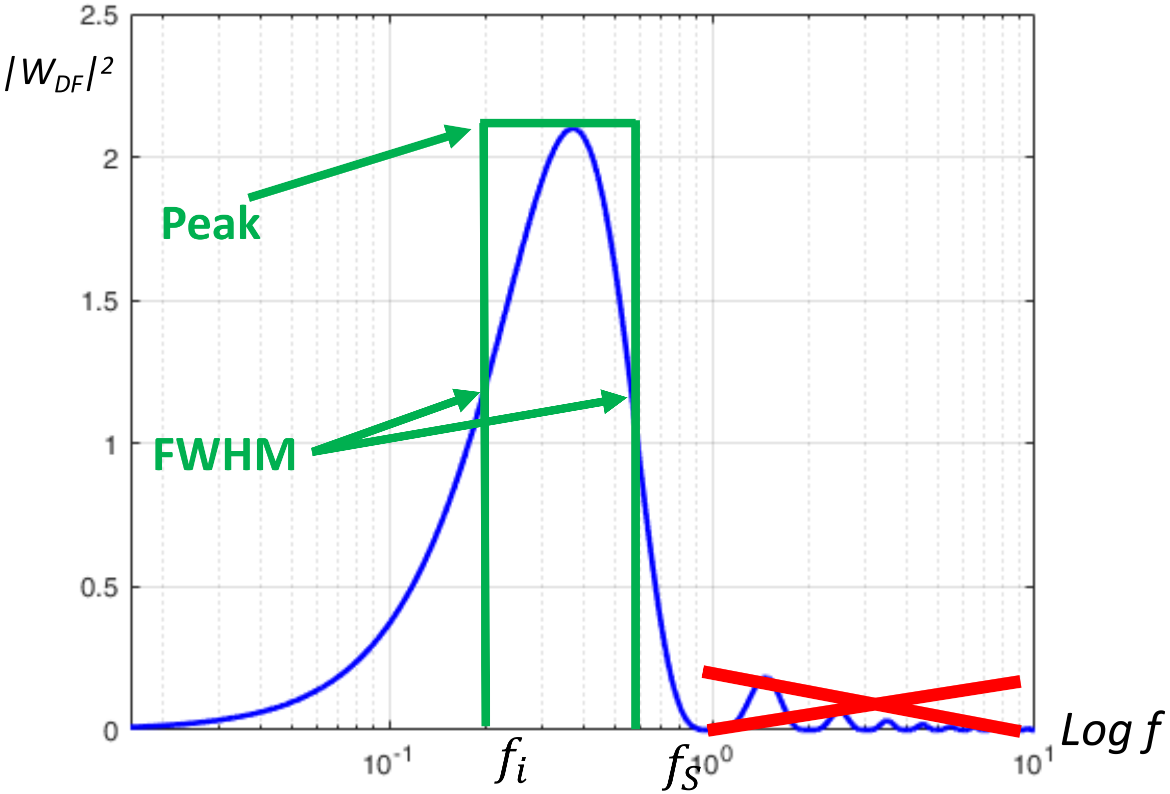
Using Matlab we can plot the $|W_{DF}|^2$:



Computed for the case of time shift $T = T_F$ integration time = 1

Let’s try to approximate the computation in this particular (and really common) case

Approximation of CDF with GI



Computed for the case of time shift T = T_F integration time = 1

The noise is the integral in the Lin-Log plot:

$$\overline{n_f^2} = S_B\ f_c \int_{-\infty}^{\infty} |W(f)|^2 d(\ln f)$$

We can approximate it with the first lobe

We would like to calculate the noise, and so the area, just like a rect, in the Lin-Log domain we have:

$$Area =\approx Peak * \ln\left(\frac{f_S}{f_i}\right)$$

From the Matlab plot we can derive: $f_i \approx$ 0,2 and $f_S \approx$ 0,6 and Peak ≈2,1

So we can finally calculate the noise as:

$$\overline{n_f^2} = S_B\ f_c \int_{-\infty}^{\infty} |W(f)|^2 d(\ln f) = S_B\ f_c * Area\ = S_B\ f_c * Peak * \ln\left(\frac{f_S}{f_i}\right) = S_B\ f * 2{,}1 * \ln\left(\frac{0{,}6}{0{,}2}\right)$$

$$\overline{n_f^2} = S_B\ f_c{*}2{,}3$$

The precise integral computation would be 2,7, just 15% more